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Docket No.: S4-02P1162

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Heres, certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Wandria, VA 22373-1467, on the date indicated below.

Ву:

Date: August 18, 2005

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No.

10/528,588

Confirmation No: N/A

Applicant

Bernd Meier, et al.

Filed Title March 21, 2005
Circuit Arrangement for Averaging

Art Unit

N/A

Examiner

to be assigned

Docket No. :

S4-02P11627

Customer No.:

24131

## INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner for Patents

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

James C. Candy, et al.: "Oversampling Delta-Sigma Data Converters", Theory, Design and Simulation. The Institute of Electrical and Electronics Engineers, Inc., New York, December 1988, pp. 293-303;

Steven R. Norsworthy, et al.: "Delta-Sigma Data Converters", Theory, Design and Simulation. The Institute of Electrical and Electronics Engineers, Inc., New York, 1997, pp. 1-43;

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Jürgen van Engelen, et al.: "Bandpass Sigma Delta Modulators", Stability Analysis, Performance and Design Aspects. 2000 ISBN: 0-7923-8698-1, pp 1.

Respectfully submitted,

For Applicants

Date: August 18, 2005

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Alfred K. Dassler 52,794

FORM	PTO-1449	(SUBST	TUTE

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

SATEMENT BY APPLICANT
(37 CFR 1.98(b))

Attorney Do	cket	No.:
S4-02P11	627	,

Applic. No. 10/528,588

Applicant

Bernd Meier, et al.

Filing Date

Group Art Unit

March 21, 2005

N/A

## **U.S. PATENT DOCUMENTS**

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
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## FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRAI YES	NSL.   NO
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

0	James C. Candy et al.: "Oversampling Delta-Sigma Data Converters", Theory, Design and Simulation. The Institute of Electrical and Electronics Engineers, Inc., New York, December 1988, pp. 293-303
	Steven R. Norsworthy, et al.: "Delta-Sigma Data Converters", Theory, Design and Simulation. The Institute of Electrical and Electronics Engineers, Inc., New York, 1997, pp. 1-43

**EXAMINER** 

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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		0	Jürgen van Engelen, et al.: "Bandpass Sigma Delta Modulators",						
	Stability Analysis, Performance and Design Aspects. 2000 ISBN:						BN:		
		0-7923-8698-1, pp 1							
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